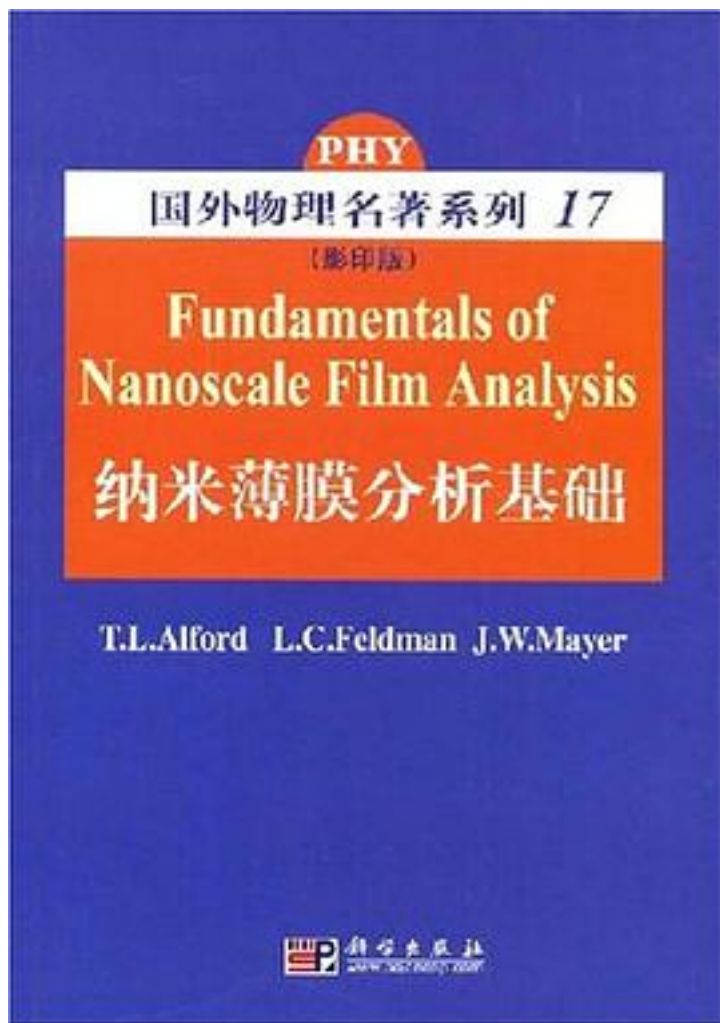


# 纳米薄膜分析基础



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《纳米薄膜分析基础17(影印版)》讨论了通过入射光子或粒子刻蚀纳米材料来表征材料

的方法，入射的粒子能够激发出可测的粒子或光子，这正是表征材料的依据，纳米尺度材料分析实验会用到大量入射粒子与待测粒子束的相互作用。其中较重要的有原子碰撞、卢瑟福背散射、离子遂道、衍射、光子吸收、辐射与非辐射阳县跃迁以及核反应。《纳米薄膜分析基础17(影印版)》详细介绍了各种分析和扫描探针显微技术。

现代科学技术（从材料科学到集成电路）已深入到纳米层次。从薄膜到场效应传感器，研究的重点是如何把尺度从微米量级减小到纳米量级。纳米薄膜分析一书主要研究了材料表面及从表面到几十乃至100纳米深的结构与构成。主要讨论了用入射粒子和光子来量化结构并进行成分和深度分析的材料表征方法。

作者介绍:

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